FAIRCHILD SEMICONDUCTOR™

May 1998

74LVQ157
Low Voltage Quad 2-Input Multiplexer

General Description

The LVQ157 is a high-speed quad 2-input multiplexer. Four bits of data from two sources can be selected using the common Select and Enable inputs. The four outputs present the selected data in the true (noninverted) form. The LVQ157 can also be used as a function generator.

Features

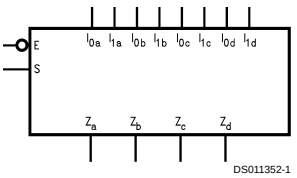
- Ideal for low power/low noise 3.3V applications
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Guaranteed pin-to-pin skew AC performance
- Guaranteed incident wave switching into 75Ω.

Ordering Code:

Order Number	Package Number	Package Description
74LVQ157SC	M16A	16-Lead (0.150" Wide) Small Outline Integrated Circuit, SOIC JEDEC
74LVQ157SJ	M16D	16-Lead Molded Small Outline Package, SOIC EIAJ

Devices also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.

Logic Symbols



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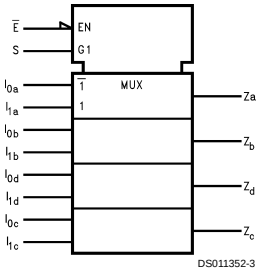
IEEE/IEC



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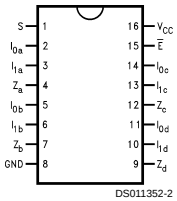
Connection Diagram

Pin Assignment for SOIC JEDEC and EIAJ



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Pin Descriptions

Pin Names	Description
I_{0a}–I_{0d}	Source 0 Data Inputs
I_{1a}–I_{1d}	Source 1 Data Inputs
$\overline{E}$	Enable Input
S	Select Input
Z_a–Z_d	Outputs

Truth Table

Inputs				Outputs
$\overline{E}$	S	I_0	I_1	Z
H	X	X	X	L
L	H	X	L	L
L	H	X	H	H
L	L	L	X	L
L	L	H	X	H

H = HIGH Voltage Level
L = LOW Voltage Level
X = Immaterial

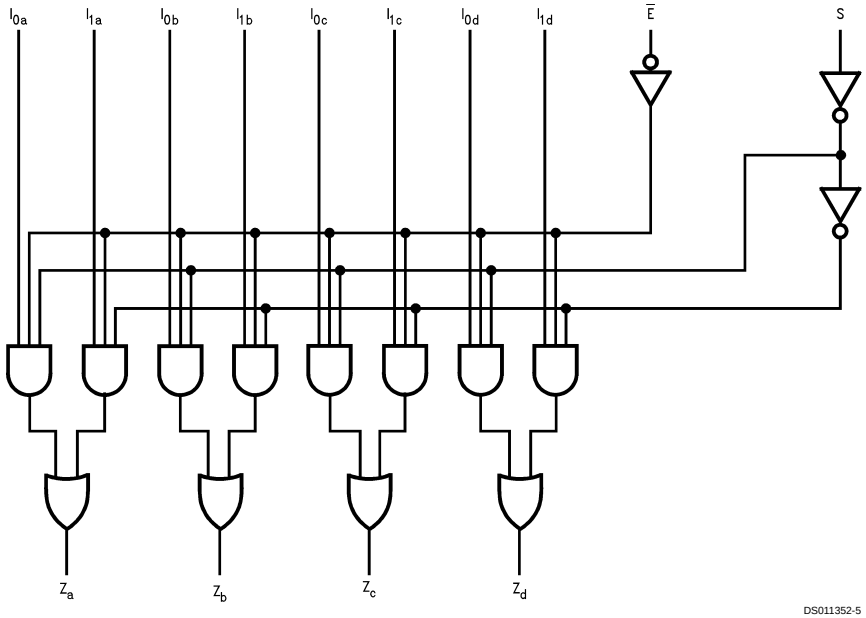
Functional Description

The LVQ157 is a quad 2-input multiplexer. It selects four bits of data from two sources under the control of a common Select input (S). The Enable input ($\overline{E}$) is active-LOW. When $\overline{E}$ is HIGH, all of the outputs (Z) are forced LOW regardless of all other inputs. The LVQ157 is the logic implementation of a 4-pole, 2-position switch where the position of the switch is determined by the logic levels supplied to the Select input. The logic equations for the outputs are shown below:

$Z_a = \overline{E} \bullet (I_{1a} \bullet S + I_{0a} \bullet \overline{S})$
$Z_b = \overline{E} \bullet (I_{1b} \bullet S + I_{0b} \bullet \overline{S})$
$Z_c = \overline{E} \bullet (I_{1c} \bullet S + I_{0c} \bullet \overline{S})$
$Z_d = \overline{E} \bullet (I_{1d} \bullet S + I_{0d} \bullet \overline{S})$

A common use of the LVQ157 is the moving of data from two groups of registers to four common output busses. The particular register from which the data comes is determined by the state of the Select input. A less obvious use is as a function generator. The LVQ157 can generate any four of the sixteen different functions of two variables with one variable common. This is useful for implementing gating functions.

Logic Diagram



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Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings (Note 1)

Supply Voltage (V_{CC})	−0.5V to +7.0V
DC Input Diode Current (I_{IK})	
V_I = −0.5V	−20 mA
V_I = V_{CC} + 0.5V	+20 mA
DC Input Voltage (V_I)	−0.5V to V_{CC} + 0.5V
DC Output Diode Current (I_{OK})	
V_O = −0.5V	−20 mA
V_O = V_{CC} + 0.5V	+20 mA
DC Output Voltage (V_O)	−0.5V to V_{CC} + 0.5V
DC Output Source or Sink Current (I_O)	±50 mA
DC V_{CC} or Ground Current (I_{CC} or I_{GND})	±200 mA
Storage Temperature (T_{STG})	−65˚C to +150˚C
DC Latch-Up Source or Sink Current	±100 mA

Recommended Operating Conditions (Note 2)

Supply Voltage (V_{CC})	2.0V to 3.6V
Input Voltage (V_I)	0V to V_{CC}
Output Voltage (V_O)	0V to V_{CC}
Operating Temperature (T_A)	−40˚C to +85˚C
Minimum Input Edge Rate (ΔV/Δt)	
V_{IN} from 0.8V to 2.0V	
V_{CC} @ 3.0V	125 mV/ns

Note 1: The "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characteristics tables are not guaranteed at the absolute maximum ratings. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

Note 2: Unused inputs must be held HIGH or LOW. They may not float.

DC Electrical Characteristics

Symbol	Parameter	V_{CC} (V)	T_A = +25˚C		T_A = −40˚C to +85˚C	Units	Conditions
			Typ	Guaranteed Limits			
V_{IH}	Minimum High Level Input Voltage	3.0	1.5	2.0	2.0	V	V_{OUT} = 0.1V or V_{CC} − 0.1V
V_{IL}	Maximum Low Level Input Voltage	3.0	1.5	0.8	0.8	V	V_{OUT} = 0.1V or V_{CC} − 0.1V
V_{OH}	Minimum High Level Output Voltage	3.0	2.99	2.9	2.9	V	I_{OUT} = −50 μA
		3.0		2.58	2.48	V	V_{IN} = V_{IL} or V_{IH} (Note 3) I_{OH} = −12 mA
V_{OL}	Maximum Low Level Output Voltage	3.0	0.002	0.1	0.1	V	I_{OUT} = 50 μA
		3.0		0.36	0.44	V	V_{IN} = V_{IL} or V_{IH} (Note 3) I_{OL} = 12 mA
I_{IN}	Maximum Input Leakage Current	3.6		±0.1	±1.0	μA	V_I = V_{CC}, GND
I_{OLD}	Minimum Dynamic	3.6			36	mA	V_{OLD} = 0.8V Max (Note 5)
I_{OHD}	Output Current (Note 4)	3.6			−25	mA	V_{OHD} = 2.0V Min (Note 5)
I_{CC}	Maximum Quiescent Supply Current	3.6		4.0	40.0	μA	V_{IN} = V_{CC} or GND
V_{OLP}	Quiet Output Maximum Dynamic V_{OL}	3.3	0.7	0.8		V	(Notes 6, 7)
V_{OLV}	Quiet Output Minimum Dynamic V_{OL}	3.3	−0.4	−0.8		V	(Notes 6, 7)
V_{IHD}	Maximum High Level Dynamic Input Voltage	3.3	1.7	2.0		V	(Notes 6, 8)
V_{ILD}	Maximum Low Level Dynamic Input Voltage	3.3	1.6	0.8		V	(Notes 6, 8)

Note 3: All outputs loaded; thresholds on input associated with output under test.

Note 4: Maximum test duration 2.0 ms, one output loaded at a time.

Note 5: Incident wave switching on transmission lines with impedances as low as 75Ω for commercial temperature range is guaranteed for.

Note 6: Worst case package.

Note 7: Max number of outputs defined as (n). Data inputs are driven 0V to 3.3V; one output at GND.

Note 8: Max number of Data Inputs (n) switching. (n − 1) inputs switching 0V to 3.3V. Input-under-test switching: 3.3V to threshold (V_{ILD}), 0V to threshold (V_{IHD}), f = 1 MHz.

AC Electrical Characteristics

Symbol	Parameter	V_{CC} (V)	T_A = +25°C, C_L = 50 pF			T_A = −40°C to +85°C, C_L = 50 pF		Units
			Min	Typ	Max	Min	Max	
t_{PLH}	Propagation Delay	2.7	1.5	84	16.2	1.5	19.0	ns
	S to Z_n	3.3 ±0.3	1.5	7.0	11.5	1.5	13.0	
t_{PHL}	Propagation Delay	2.7	1.5	7.8	15.5	1.5	17.0	ns
	S to Z_n	3.3 ±0.3	1.5	6.5	11.0	1.5	12.0	
t_{PLH}	Propagation Delay	2.7	1.5	8.4	16.2	1.5	19.0	ns
	$\overline{E}$ to Z_n	3.3 ±0.3	1.5	7.0	11.5	1.5	13.0	
t_{PHL}	Propagation Delay	2.7	1.5	7.8	15.5	1.5	17.0	ns
	$\overline{E}$ to Z_n	3.3 ±0.3	1.5	6.5	11.0	1.5	12.0	
t_{PLH}	Propagation Delay	2.7	1.5	6.0	12.0	1.0	13.0	ns
	I_n to Z_n	3.3 ±0.3	1.5	5.0	8.5	1.0	9.0	
t_{PHL}	Propagation Delay	2.7	1.5	6.0	11.3	1.0	13.0	ns
	I_n to Z_n	3.3 ±0.3	1.5	5.0	8.0	1.0	9.0	
t_{OSHL},	Output to Output Skew (Note 9)	2.7		1.0	1.5		1.5	ns
t_{OSLH}	Data to Output	3.3 ±0.3		1.0	1.5		1.5	

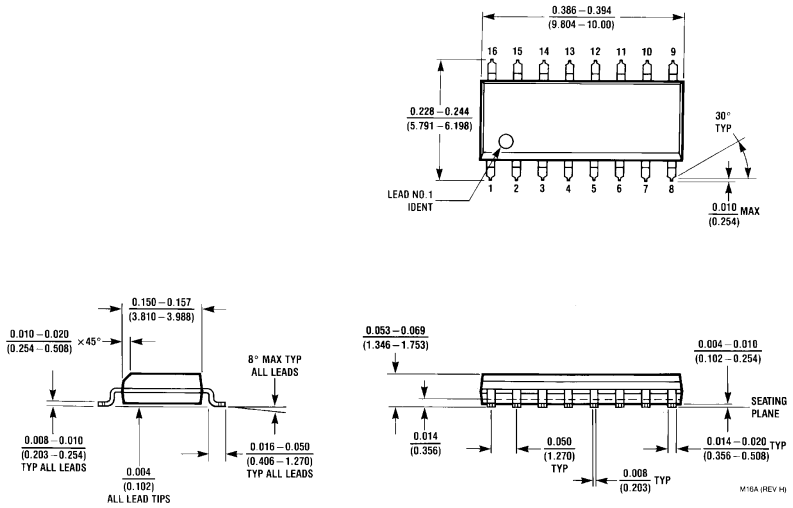
Note 9: Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH to LOW (t_{OSHL}) or LOW to HIGH (t_{OSLH}). Parameter guaranteed by design.

Capacitance

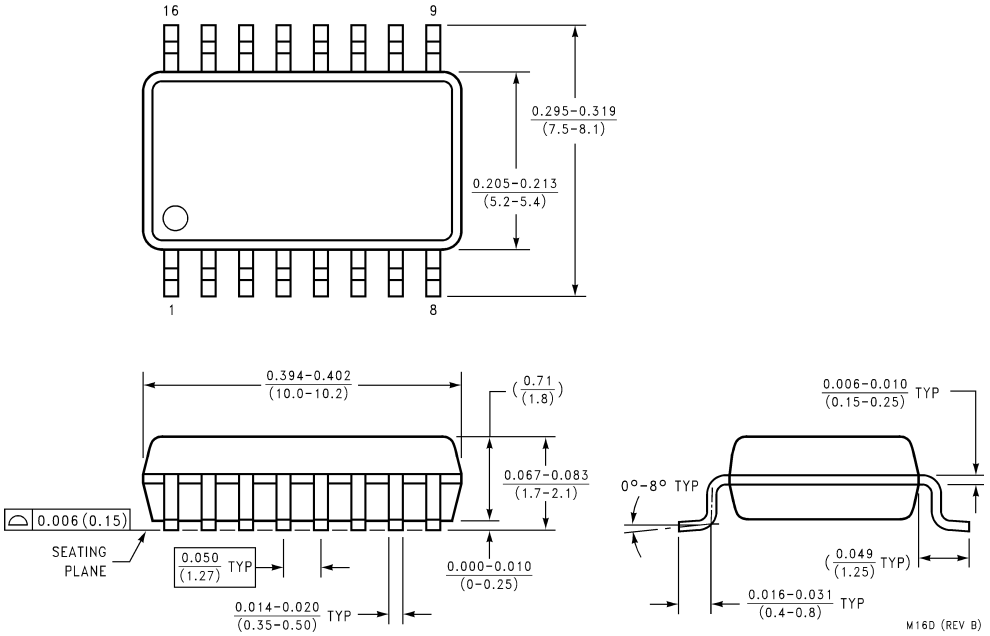
Symbol	Parameter	Typ	Units	Conditions
C_{IN}	Input Capacitance	4.5	pF	V_C = Open
C_{PD} (Note 10)	Power Dissipation Capacitance	34.0	pF	V_{CC} = 3.3V

Note 10: C_{PD} is measured at 10 MHz.

Physical Dimensions inches (millimeters) unless otherwise noted



16-Lead (0.150" Wide) Small Outline Integrated Circuit, SOIC JEDEC
Package Number M16A



16-Lead Molded Small Outline Package, SOIC EIAJ
Package Number M16D

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